NEC

MOS FIELD EFFECT TRANSISTOR

2SK3357

SWITCHING
N-CHANNEL POWER MOS FET
INDUSTRIAL USE

DESCRIPTION

The 2SK3357 is N-channel MOS Field Effect Transistor designed for high current switching applications.

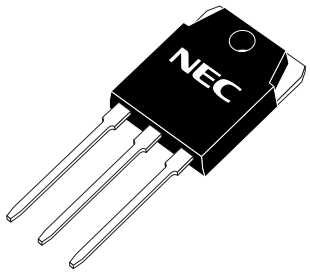
ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3357	TO-3P

FEATURES

- Super low on-state resistance:
  $R_{DS(on)1}$ = 5.8 mΩ MAX. (V_{GS} = 10 V, I_D = 38 A)
  $R_{DS(on)2}$ = 8.8 mΩ MAX. (V_{GS} = 4.0 V, I_D = 38 A)
- Low C_{iss}: C_{iss} = 9800 pF TYP.
- Built-in gate protection diode

(TO-3P)



ABSOLUTE MAXIMUM RATINGS (T_A = 25°C)

Drain to Source Voltage	V_{DSS}	60	V
Gate to Source Voltage	$V_{GSS(AC)}$	±20	V
Drain Current (DC)	$I_{D(DC)}$	±75	A
Drain Current (pulse) Note1	$I_{D(pulse)}$	±300	A
Total Power Dissipation (T_C = 25°C)	P_T	150	W
Total Power Dissipation (T_A = 25°C)	P_T	3.0	W
Channel Temperature	T_{ch}	150	°C
Storage Temperature	T_{stg}	–55 to +150	°C
Single Avalanche Current Note2	I_{AS}	75	A
Single Avalanche Energy Note2	E_{AS}	562	mJ

Notes 1. PW ≤ 10 μs, Duty cycle ≤ 1 %

2. Starting T_{ch} = 25°C, R_G = 25 Ω, V_{GS} = 20 V → 0 V

THERMAL RESISTANCE

Channel to Case	$R_{th(ch-C)}$	0.83	°C/W
Channel to Ambient	$R_{th(ch-A)}$	41.7	°C/W

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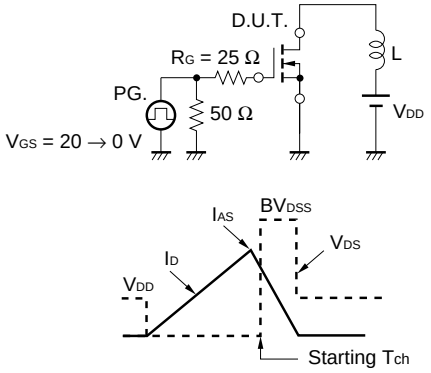
The mark ★ shows major revised points.

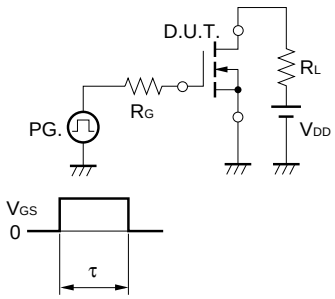
ELECTRICAL CHARACTERISTICS (T_A = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	$R_{DS(on)1}$	V_{GS} = 10 V, I_D = 38 A		4.6	5.8	mΩ
	$R_{DS(on)2}$	V_{GS} = 4.0 V, I_D = 38 A		6.1	8.8	mΩ
Gate to Source Cut-off Voltage	$V_{GS(off)}$	V_{DS} = 10 V, I_D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	$\|y_{fs}\|$	V_{DS} = 10 V, I_D = 38 A	38	72		S
Drain Leakage Current	I_{DSS}	V_{DS} = 60 V, V_{GS} = 0 V			10	μA
Gate to Source Leakage Current	I_{GSS}	V_{GS} = ±20 V, V_{DS} = 0 V			±10	μA
Input Capacitance	C_{iss}	V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz		9800		pF
Output Capacitance	C_{oss}			1500		pF
Reverse Transfer Capacitance	C_{rss}			630		pF
Turn-on Delay Time	$t_{d(on)}$	I_D = 38 A, $V_{GS(on)}$ = 10 V, V_{DD} = 30 V,		105		ns
Rise Time	t_r	R_G = 10 Ω		1350		ns
Turn-off Delay Time	$t_{d(off)}$			500		ns
Fall Time	t_f			480		ns
Total Gate Charge	Q_G	I_D = 75 A , V_{DD} = 48 V, V_{GS} = 10 V		170		nC
Gate to Source Charge	Q_{GS}			28		nC
Gate to Drain Charge	Q_{GD}			46		nC
Body Diode Forward Voltage	$V_{F(S-D)}$	I_F = 75 A, V_{GS} = 0 V		0.96		V
Reverse Recovery Time	t_{rr}	I_F = 75 A, V_{GS} = 0 V,		64		ns
Reverse Recovery Charge	Q_{rr}	di/dt = 100 A/μs		130		nC

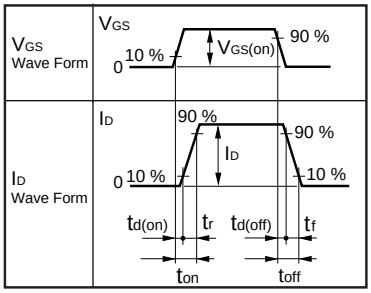
TEST CIRCUIT 1 AVALANCHE CAPABILITY



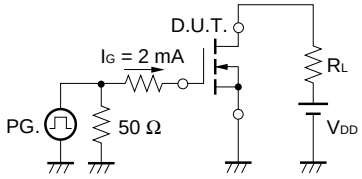
TEST CIRCUIT 2 SWITCHING TIME



τ = 1 μs
Duty Cycle ≤ 1 %

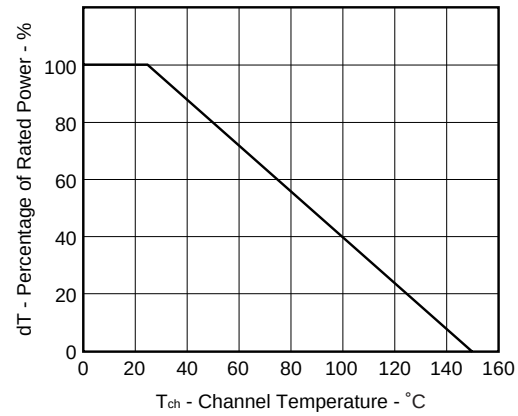


TEST CIRCUIT 3 GATE CHARGE

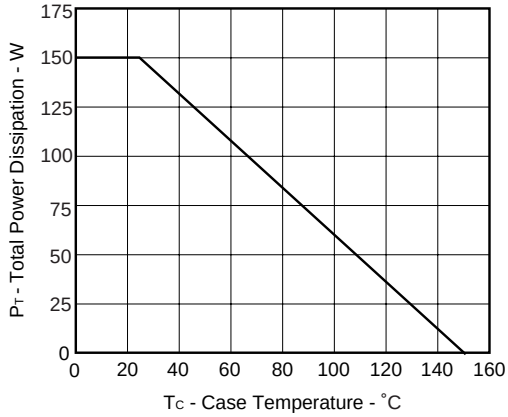


★ TYPICAL CHARACTERISTICS (T_A = 25 °C)

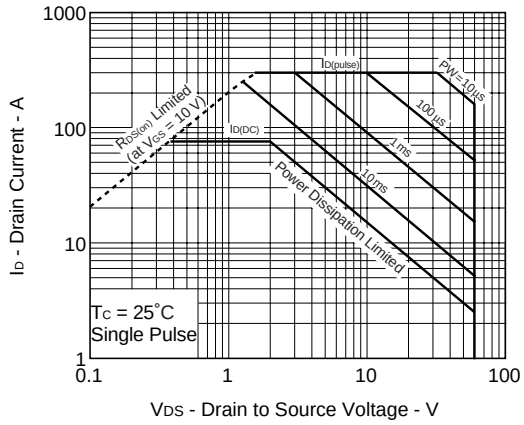
DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA



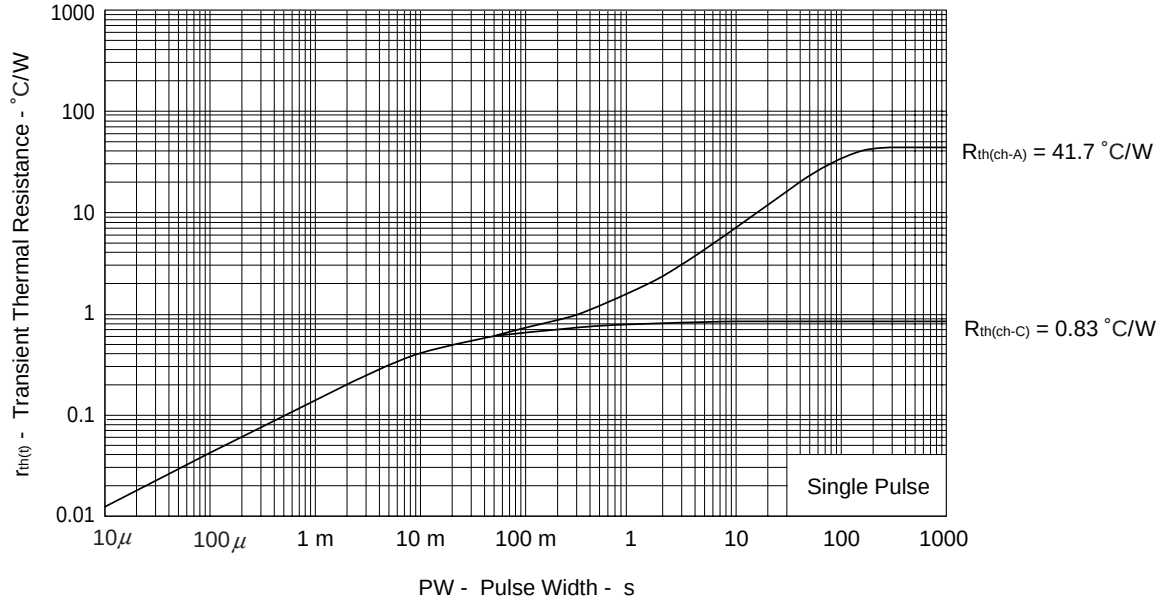
TOTAL POWER DISSIPATION vs. CASE TEMPERATURE



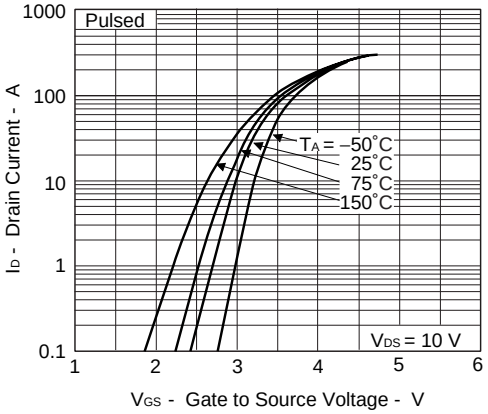
FORWARD BIAS SAFE OPERATING AREA



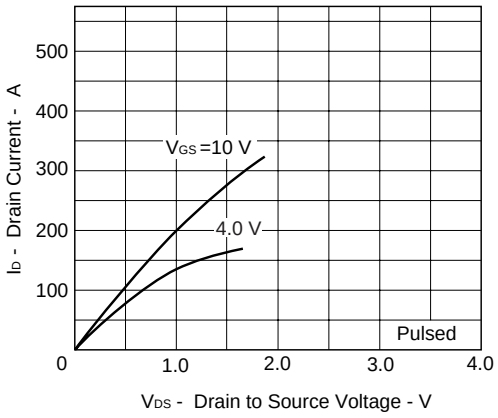
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



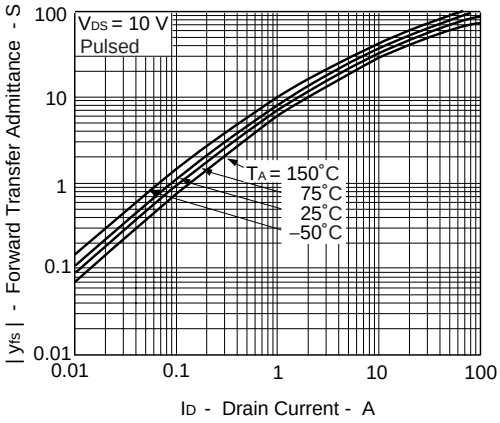
FORWARD TRANSFER CHARACTERISTICS



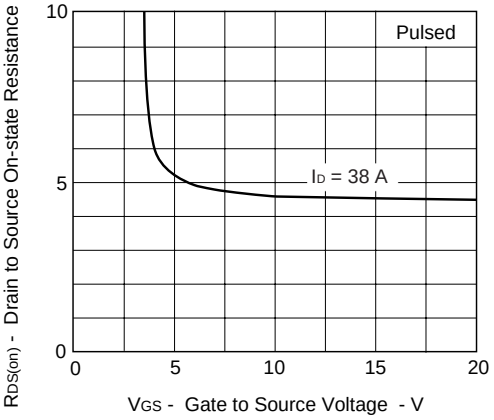
DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE



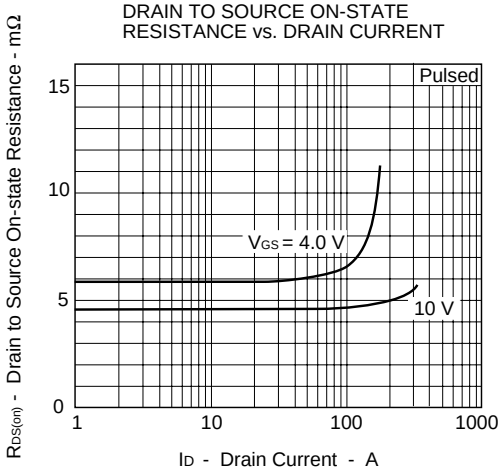
FORWARD TRANSFER ADMITTANCE vs.
DRAIN CURRENT



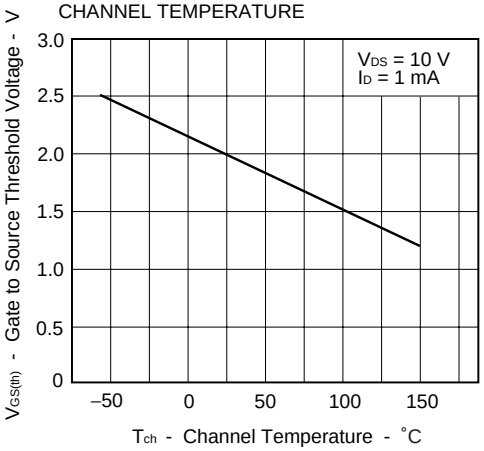
DRAIN TO SOURCE ON-STATE RESISTANCE vs.
GATE TO SOURCE VOLTAGE



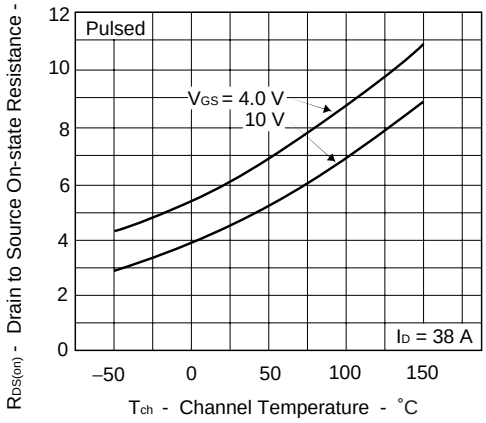
DRAIN TO SOURCE ON-STATE
RESISTANCE vs. DRAIN CURRENT



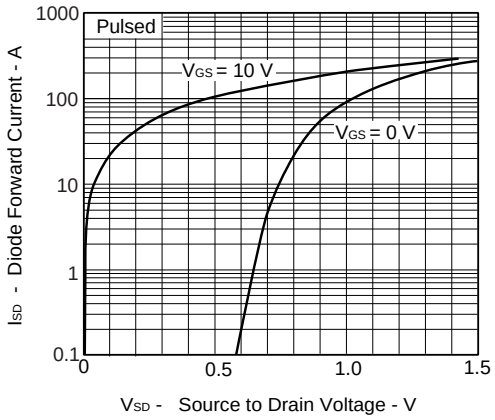
GATE TO SOURCE THRESHOLD VOLTAGE vs.
CHANNEL TEMPERATURE



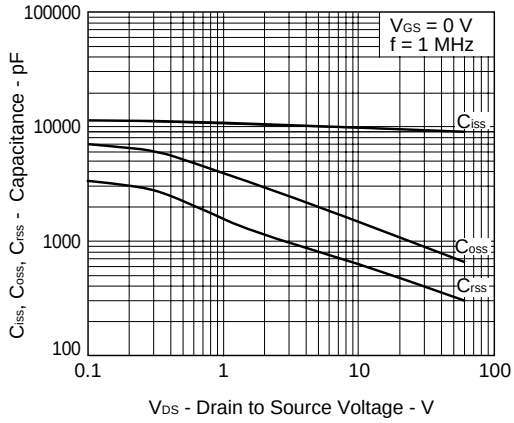
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



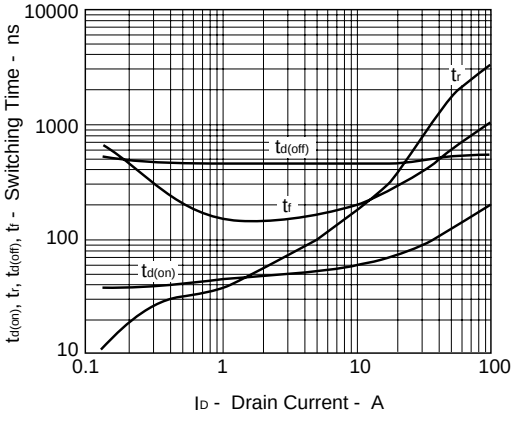
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



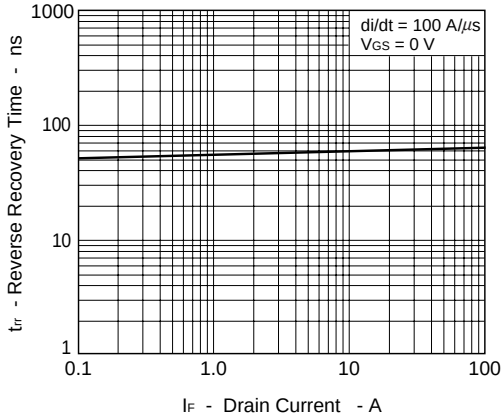
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



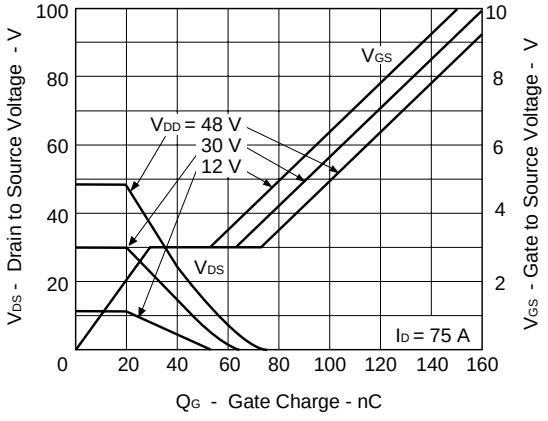
SWITCHING CHARACTERISTICS



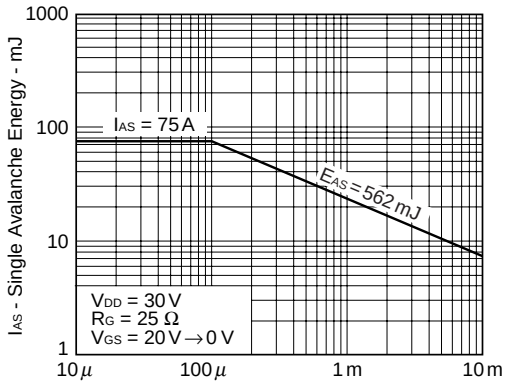
REVERSE RECOVERY TIME vs. DRAIN CURRENT



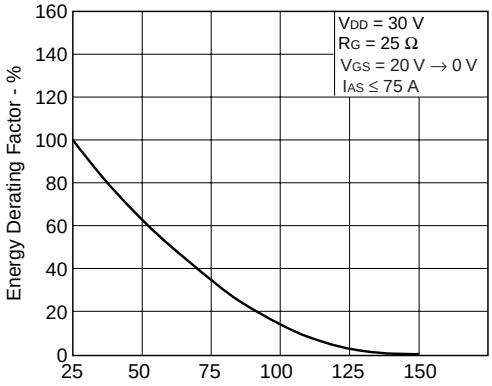
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SINGLE AVALANCHE ENERGY vs.
INDUCTIVE LOAD

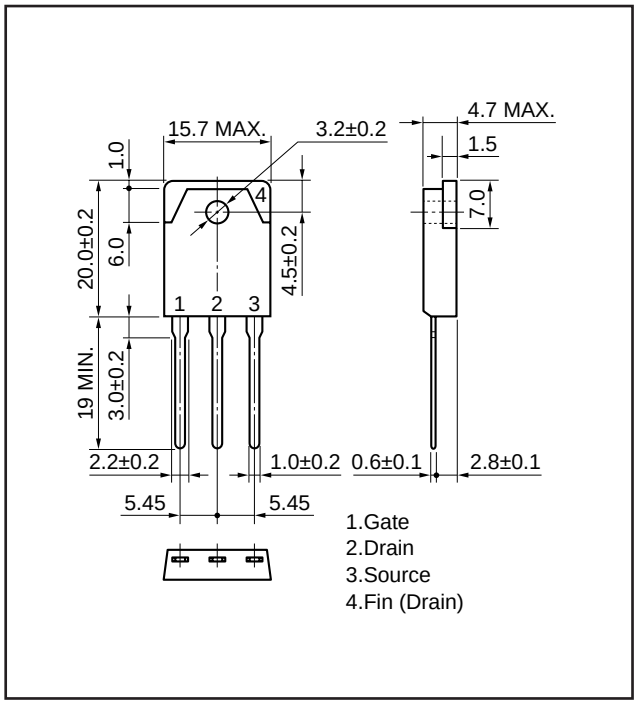


SINGLE AVALANCHE ENERGY
DERATING FACTOR

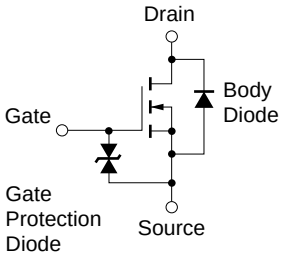


PACKAGE DRAWING (Unit: mm)

TO-3P (MP-88)



EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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